

UTC UNISONIC TECHNOLOGIES CO., LTD

4N60-R **Preliminary Power MOSFET**

4A, 600V N-CHANNEL **POWER MOSFET**

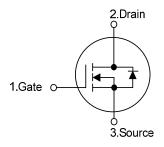
DESCRIPTION

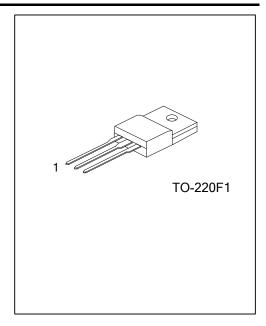
The UTC 4N60-R is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)}$ < 2.5 Ω @ V_{GS} = 10 V
- * Fast Switching Capability
- * Avalanche Energy Specified
- * Improved dv/dt Capability, high Ruggedness



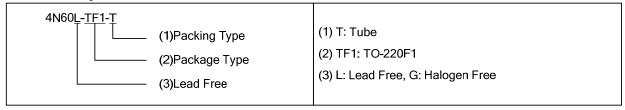




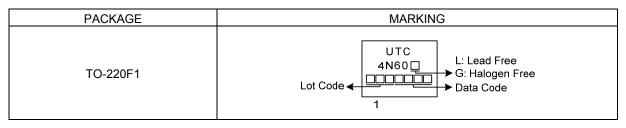
ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
4N60L-TF1-T	4N60G-TF1-T	TO-220F1	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING INFORMATION



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	600	V
Gate-Source Voltage		V_{GSS}	±30	V
Avalanche Current (Note 2)		I_{AR}	4	Α
Drain Current	Continuous	I_{D}	4.0	Α
	Pulsed (Note 2)	I_{DM}	16	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	160	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation		P_{D}	36	W
Junction Temperature		T_J	+150	°C
Operating Temperature		T_OPR	-55 ~ + 150	°C
Storage Temperature		T_{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 20mH, I_{AS} = 4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 4. $I_{SD} \le 4.4A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ.Ic	3.47	°C/W	

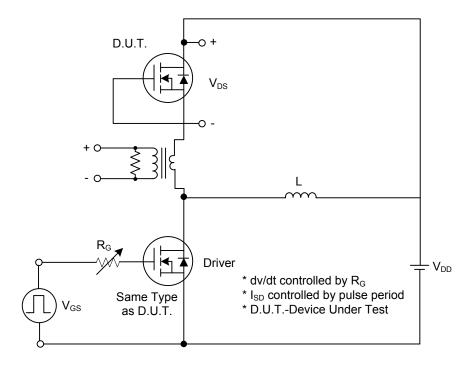
■ **ELECTRICAL CHARACTERISTICS** (T_C =25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V _{GS} =0V, I _D =250μA	600			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =600V, V _{GS} =0V			10	μΑ
			V _{DS} =480V, T _C =125°C			100	μΑ
Gate-Source Leakage Current	Forward	- I _{GSS}	V_{GS} =30V, V_{DS} =0V			100	nA
	Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_J$	I _D =250μA,Referenced to 25°C		0.6		V/°C
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	3.0		5.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10 V, I _D =2.2A		2.3	2.5	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}			440	670	pF
Output Capacitance		Coss	V_{DS} =25V, V_{GS} =0V, f =1MHz		50	100	pF
Reverse Transfer Capacitance		C_{RSS}			6.8	20	pF
SWITCHING CHARACTERISTIC	S						
Turn-On Delay Time		$t_{D(ON)}$			45	60	ns
Turn-On Rise Time		t_{R}	V_{DD} =30V, I_{D} =0.5A, R_{G} =25 Ω		35	55	ns
Turn-Off Delay Time		$t_{D(OFF)}$	(Note 1, 2)		65	85	ns
Turn-Off Fall Time		t_{F}			40	60	ns
Total Gate Charge		Q_G	 V _{DS} =50V, I _D =1.3A, I _D =100μA		15	30	nC
Gate-Source Charge		Q_GS	V _{GS} =10V (Note 1, 2)		5		nC
Gate-Drain Charge		Q_GD	VGS-10V (Note 1, 2)		15		nC
SOURCE- DRAIN DIODE RATIN	GS AND CI	HARACTERIS'	rics				
Drain-Source Diode Forward Voltage		V_{SD}	V _{GS} =0V, I _S =4.4A			1.4	V
Maximum Continuous Drain-Source Diode		Is				4.4	Α
Forward Current						7.7	^
Maximum Pulsed Drain-Source Diode		I _{SM}				17.6	Α
Forward Current						17.5	, , ,
Reverse Recovery Time		t _{rr}	V _{GS} =0 V, I _S =4.4A,		250		ns
Reverse Recovery Charge		Q_{RR}	dI _F /dt=100 A/μs (Note 1) 1.		1.5		μC

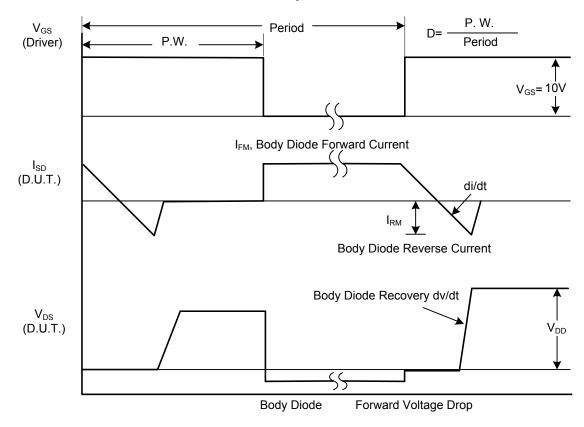
Notes: 1. Pulse Test: Pulse width≤300µs, Duty cycle≤2%

^{2.} Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

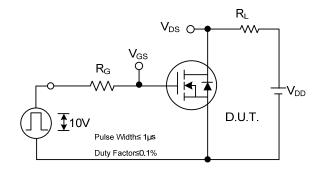


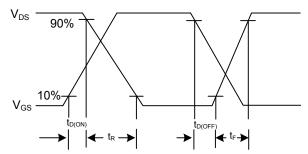
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

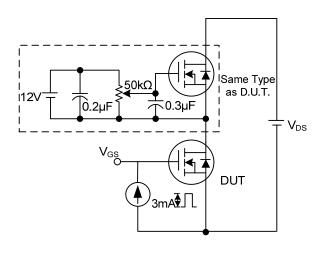
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

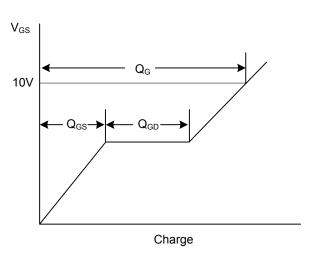




Switching Test Circuit

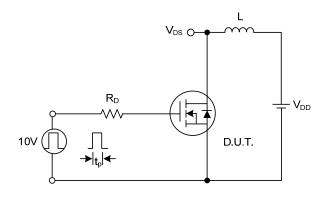
Switching Waveforms

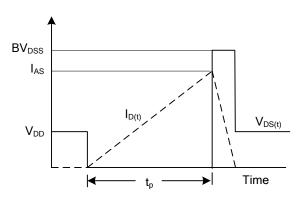




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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